

ABSTRACT OF THE DISCLOSURE

The present invention relates to a method of measuring the luminescence emitted in a luminescent assay, which makes it possible to correct certain perturbations due to the measuring medium.

Said method comprises employing at least one luminescent tracer compound and a luminescent compound used as an internal reference, which, when exposed to the same excitation wavelength, are capable of emitting at different wavelengths, λ_2 and λ_1 respectively, either by direct luminescence or by the induction of a luminescent emission, and correcting the measurement of the luminescence emitted by the tracer compound at wavelength λ_2 on the basis of the measurement of the luminescence emitted by the reference compound at wavelength λ_1 .

The invention further relates to the use of said method in a homogeneous method of detecting and/or determining an analyte, and to a device for carrying it out.

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